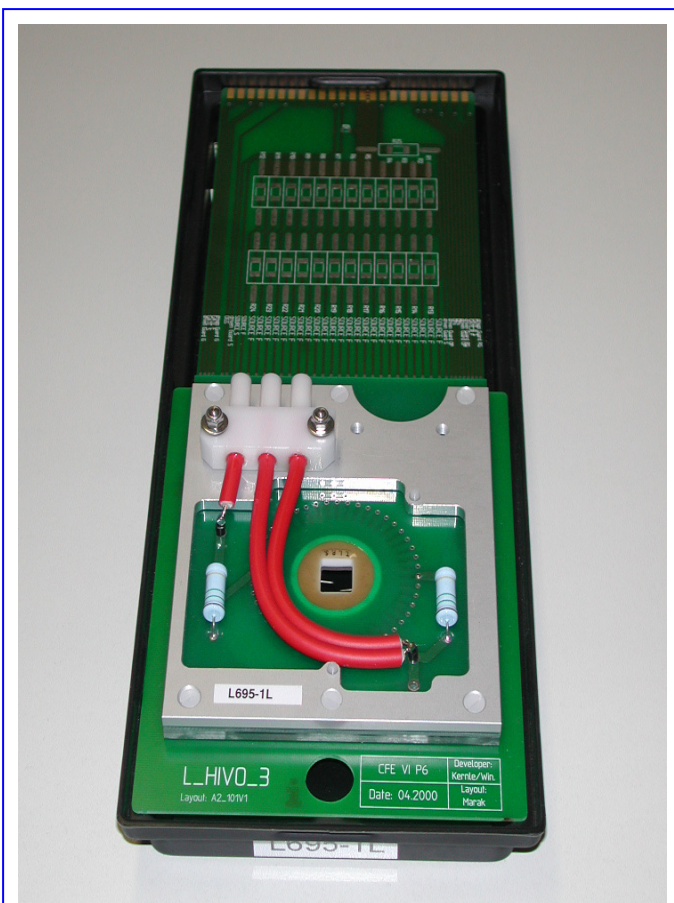


## Probe Cards for Power Semiconductors

Wafer test of power semiconductor poses some quite specific challenges as test currents as high as 100 Amps and test voltages in the range of several Kilovolts.

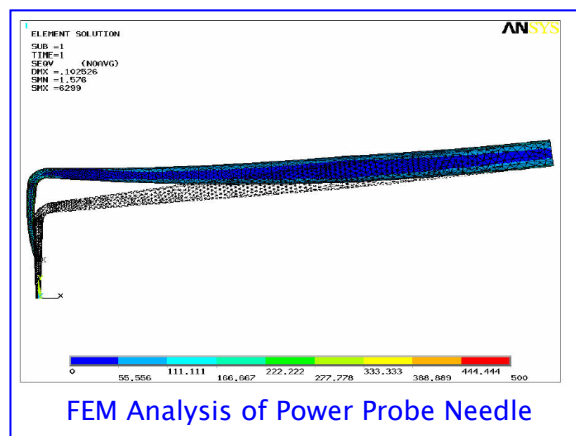


10 kV High Voltage Probe Card

A proprietary **probe tip reshaping** and maintenance process ensures the full performance of the probe card over the life span – either by T.I.P.S. maintenance services or by equipment that can be provided for customers on-site probe card shop.

T.I.P.S.' probe cards for power semiconductors involve several features to cope with these extreme conditions as:

- **"Luftpolster"** probe card: testing under protective atmosphere to avoid high voltage flashovers
- **"SmartClamp"** probe card protection: Protecting probes and pad from damage due to current overload
- **"NoScrub"** and **"ShortScrub"** probe geometries allow minimal scrub mark sizes over active silicon yet maintaining excellent contact properties.



FEM Analysis of Power Probe Needle